

Refine Search

Search Results -





Terms	Documents
(semiconductor same stack) and (stack same test\$)	447

Database:

- US Pre-Grant Publication Full-Text Database
- US Patents Full-Text Database
- US OCR Full-Text Database
- EPO Abstracts Database
- JPO Abstracts Database
- Derwent World Patents Index
- IBM Technical Disclosure Bulletins

Search:

L2



Refine Search

Recall Text 

Clear

Interrupt

Search History

DATE: Tuesday, September 07, 2004 [Printable Copy](#) [Create Case](#)

Set Name Query
side by side

Hit Count Set Name
result set

DB=USPT; PLUR=YES; OP=ADJ

L2 (semiconductor same stack) and (stack same test\$) 447 L2

DB=DWPI; PLUR=YES; OP=ADJ

L1 (semiconductor same stack) and (stack same test\$) 41 L1

END OF SEARCH HISTORY